

Description

The AP40P04DF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = -40V I_{D} = -40 A$

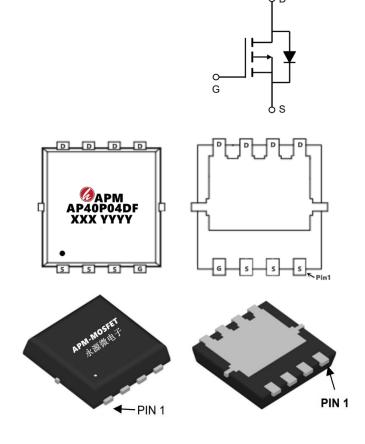
 $R_{DS(ON)} < 18m\Omega$ @ V_{GS} =-10V (Type: 15m Ω)

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP40P04DF	PDFN3*3-8L	AP40P04DF XXX YYYY	5000

Absolute Maximum Ratings (TC=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units	
VDS	Drain-Source Voltage	-40	V	
Vgs	Gate-Source Voltage	±20	V	
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ -10V ¹	-40	А	
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ -10V ¹	-23	А	
Ірм	Pulsed Drain Current ²	-120	Α	
EAS	Single Pulse Avalanche Energy ³	125	mJ	
P _D @T _C =25°C	Total Power Dissipation ⁴	25	W	
P _D @T _A =25°C	Total Power Dissipation ⁴	16	W	
Тѕтс	Storage Temperature Range	-55 to 150	°C	
TJ	Operating Junction Temperature Range	-55 to 150	°C	
R _θ JA	Thermal Resistance Junction-Ambient ¹	85	°C/W	
Rejc	Thermal Resistance Junction-Case ¹	5	°C/W	



Electrical Characteristics (T_J=25℃, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-40	-44		V
△BVdss/△TJ	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =-1mA		-0.023		V/°C
_	Static Drain-Source On-Resistance ²	V _{GS} =-10V , I _D =-30A		15	18	mΩ
Rds(on)		V _{GS} =-4.5V , I _D =-20A		18	25	
V _{GS(th)}	Gate Threshold Voltage	\/ -\/ - 250A	-1.0	-1.6	-2.5	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	V _{GS} =V _{DS} , I _D =-250uA		4.74		mV/°C
l	V _{DS} =-40V , V _{GS} =0V , T _J =25°	V _{DS} =-40V , V _{GS} =0V , T _J =25°C			1	uA
IDSS	Drain-Source Leakage Current	V _{DS} =-40V , V _{GS} =0V , T _J =55°C			5	
Igss	Gate-Source Leakage Current	V_{GS} =±20 V , V_{DS} =0 V			±100	nA
Qg	Total Gate Charge (-4.5V)			25		
Qgs	Gate-Source Charge	V _{DS} =-20V , V _{GS} =-4.5V , I _D =-12A		11		nC
Qgd	Gate-Drain Charge	.5,		9.5		
Td(on)	Turn-On Delay Time			48		
Tr	Rise Time	VDD =-15V, RL=15Ω		24		ns
Td(off)	Turn-Off Delay Time	ID =-1A, VGEN =-10V, RG =6Ω		88		115
Tf	Fall Time			9.6		
Ciss	Input Capacitance			2760		
Coss	Output Capacitance	V _{DS} =-20V , V _{GS} =0V , f=1MHz		260		pF
Crss	Reverse Transfer Capacitance			85		
ls	Continuous Source Current ^{1,5}	V _G =V _D =0V , Force Current			-40	Α
Isм	Pulsed Source Current ^{2,5}	vg-vD-0v, Force Current			-90	Α
VsD	Diode Forward Voltage ²	V _{GS} =0V , I _S =-1A , T _J =25°C			-1.3	V

Note:

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width $\,\leqq\,300\text{us}$, duty cycle $\,\leqq\,2\%$
- 3. The EAS data shows Max. rating . The test condition is VDD=-32V,VGS=-10V,L=0.1mH,IAS=-30A
- 4. The power dissipation is limited by 150 ℃ junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



Typical Characteristics

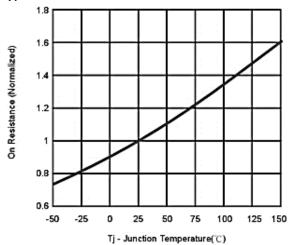
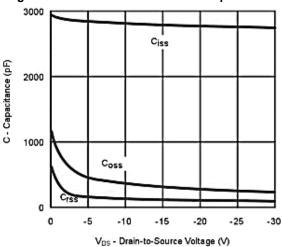


Fig.1 On Resistance Vs Junction Temperature



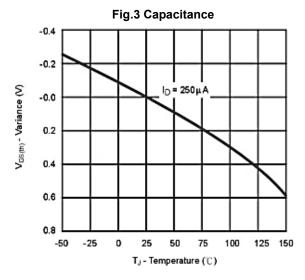


Fig.5 Threshold Voltage

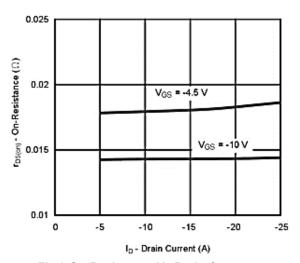


Fig.2 On-Resistance Vs.Drain Current

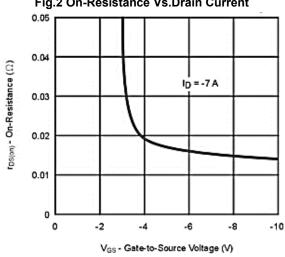


Fig.4 On-Resistance Vs. Gate-to-Sourece Voltage

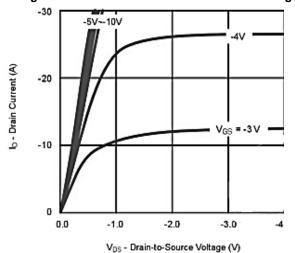


Fig.6 On-Region Characteristics





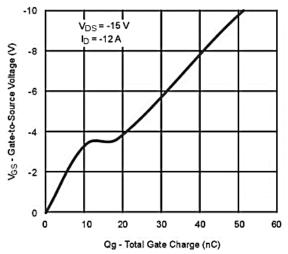


Fig.7 Gate Charge

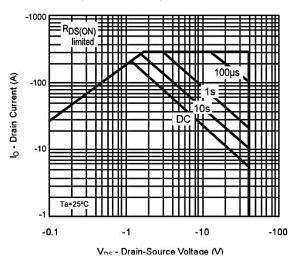


Fig.9 Safe Operating Area

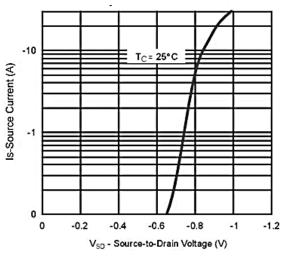


Fig.8 Body-diode Characteristice

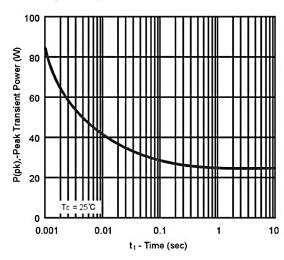


Fig.10 Single Pluse Maximum Power Dissipation

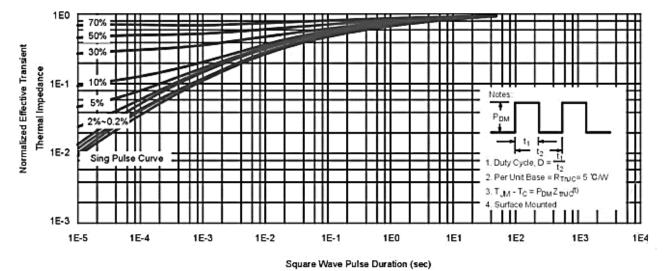
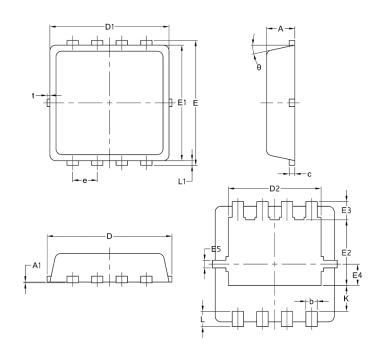


Fig.11 Normalized Maximum Transient Thermal Impedance



Package Mechanical Data-DFN3*3-8L-JQ Single



		Common		
Symbol	mm			
	Mim	Nom	Max	
Α	0.70	0.75	0.85	
A1	/	/	0.05	
b	0.20	0.30	0.40	
С	0.10	0.152	0.25	
D	3.15	3.30	3.45	
D1	3.00	3.15	3.25	
D2	2.29	2.45	2.65	
E	3.15	3.30	3.45	
E1	2.90	3.05	3.20	
E2	1.54	1.74	1.94	
E3	0.28	0.48	0.65	
E4	0.37	0.57	0.77	
E5	0.10	0.20	0.30	
е	0.60	0.65	0.70	
K	0.59	0.69	0.89	
L	0.30	0.40	0.50	
L1	0.06	0.125	0.20	
t	0	0.075	0.13	
Φ	10	12	14	



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AP40P04DF

-40V P-Channel Enhancement Mode MOSFET

Edition	Date	Change
Rve1.0	2021/8/8	Initial release

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